**Erratum: X-Ray Optics on a Chip: Guiding X Rays in Curved Channels
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T. Salditt, S. Hoffmann, M. Vassholz, J. Haber, M. Osterhoff, and J. Hilhorst
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In Fig. 1(c) we had presented finite difference (FD) simulations showing intensity spikes departing into the cladding and have interpreted these spikes as remnants of reflections in the geometric optical descriptions. Reinvestigation of the simulation has now shown that these spikes are numerical discretization artifacts. The sampling interval was sufficient to warrant convergence of the intensity distribution in the channel, but not of the intensity tails in the silicon cladding, observed on intensity scales 3–7 orders of magnitude below the incident beam. The numerical results shown on a linear scale as well as the numerical waveguide transmission values [Fig. 3(a), Fig. 4, and Fig. 5 of the Supplemental Material], which are relevant for comparison to the experiment, are not affected and remain valid.

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